# **Analysis of contamination**



## Analysis method for contamination of foreign matter

#### Observation + Foreign Matter Collection + Analysis + Report Generation

Measures against foreign matters, which is an eternal theme in electronic devices, foods, and various other fields. In order to identify the source of foreign matter and solve the problem,

It is important to select the most appropriate analytical method and how to sample small foreign matters.

## 1 Observation (Optical microscope, etc.)

Observe foreign matters using a microscope, optical microscope, etc. to check their shape and condition. Select the most appropriate analytical method by determining whether the system is **organic** (**FT-IR component analysis**) or **inorganic** (**SEM-EDX**).

2 Foreign matter collection (precision manipulator)

A few µm of foreign matters that are difficult to collect by human hands are sampled.



Sem SED 011

#### 3 Analysis of organic materials

Analyze components by using FT-IR. Identify molecular structures from the infrared absorption of organic material. Analysis of inorganic materials(metals)

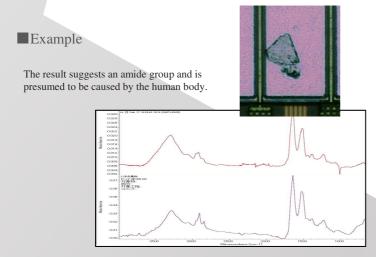
Observe with SEM-EDX.

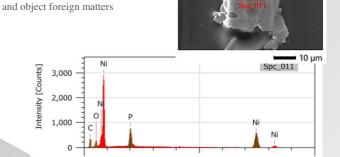
Element P and Ni detected

Identify electroless nickel plating scraps

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### Example





Energy [keV]

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We pay close attention to the details of consultations and requests with the first priority on strict adherence. In particular, a confidentiality agreement shall be entered into in the event of a request.